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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Kusumoto et al. Art Unit : 2814  
Serial No. : 09/903,339 Examiner : Theresa T. Doan  
Filed : July 10, 2001  
Title : METHOD FOR PRODUCING INSULATED GATE THIN FILM  
SEMICONDUCTOR DEVICE

**MAIL STOP AF**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the reference listed on the attached PTO-1449 form.

Submitted herewith is an English translation of the following foreign language reference, or portions thereof:

Desig. ID	Source
AL	JAPAN 06-333950 – English Abstract: DIALOG(R)File 347:JAPIO (2005); Accession No. 04662050.

This statement is being filed after a Notice of Allowance, but before payment of the issue fee. The undersigned certifies that the reference included in the information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application received on October 25, 2005, which is not more than three months prior to the filing of this information disclosure statement.

A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

11/14/2005 SZEWDIE1 00000040 09903339

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Date: 11/10/05 180.00 OP

Respectfully submitted,

  
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40310367.doc



Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-010004	Application No. 09/903,339
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Kusumoto et al.	
		Filing Date July 10, 2001	Group Art Unit 2814

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	JP 06-333950	12/02/1994	Japan			Abst.	
	AM							
	AN							
	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	